

# STC6NF30V

# N-CHANNEL 30V - $0.020~\Omega$ - 6A TSSOP8 2.5V-DRIVE STripFETTM II POWER MOSFET

#### **PRELIMINARY DATA**

TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	ΙD
STC6NF30V	30 V	< 0.025 Ω ( @ 4.5 V ) < 0.030 Ω ( @ 2.5 V )	6 A

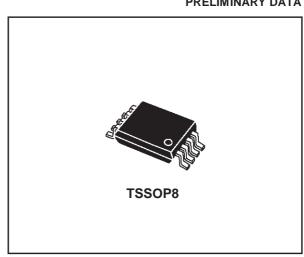
- TYPICAL  $R_{DS}(on) = 0.020 \Omega @ 4.5 V$
- TYPICAL  $R_{DS}(on) = 0.025 \Omega @ 2.5 V$
- ULTRA LOW THRESHOLD GATE DRIVE (2.5 V)
- STANDARD OUTLINE FOR EASY AUTOMATED SURFACE MOUNT ASSEMBLY

#### **DESCRIPTION**

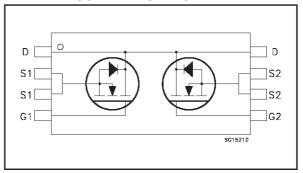
This Power MOSFET is the latest development of STMicroelectronis unique "Single Feature Size" strip-based process. The resulting transistor shows extremely high packing density for low onresistance.

### **APPLICATIONS**

- DC MOTOR DRIVE
- DC-DC CONVERTERS
- BATTERY SAFETY UNIT FOR NOMADIC **EQUIPMENT**
- POWER MANAGEMENT IN PORTABLE/DESKTOP PCs



### **INTERNAL SCHEMATIC DIAGRAM**



### **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source Voltage (V <sub>GS</sub> = 0)	30	V
$V_{DGR}$	Drain-gate Voltage ( $R_{GS} = 20 \text{ k}\Omega$ )	30	V
V <sub>GS</sub>	Gate- source Voltage	urce Voltage ± 12	
ID	Drain Current (continuous) at T <sub>C</sub> = 25°C	6	А
I <sub>D</sub>	Drain Current (continuous) at T <sub>C</sub> = 100°C	3.8	А
I <sub>DM</sub> (•)	Drain Current (pulsed)	24	А
P <sub>tot</sub>	Total Dissipation at T <sub>C</sub> = 25°C	1.25	W

(•) Pulse width limited by safe operating area.

## THERMAL DATA

Rthj-amb	Thermal Resistance Junction-ambient	Max	100	°C/W
Tj	Max. Operating Junction Temperature		150	°C
T <sub>stg</sub>	Storage Temperature		-55 to 150	°C

<sup>(\*)</sup> When Mounted on 1 in<sup>2</sup> of FR4 board

# **ELECTRICAL CHARACTERISTICS** ( $T_j$ = 25 $^{\circ}C$ unless otherwise specified)

# OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0$	30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current (V <sub>GS</sub> = 0)	$V_{DS} = Max Rating$ $V_{DS} = Max Rating T_C = 125^{\circ}C$			1 10	μA μA
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 12 V			±100	nA

## ON (\*)

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$	I <sub>D</sub> = 250 μA	0.6			V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	V <sub>GS</sub> = 4.5 V V <sub>GS</sub> = 2.5 V	$I_D = 3 A$ $I_D = 3 A$		0.020 0.025	0.025 0.030	$\Omega$

## **DYNAMIC**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
gfs (*)	Forward Transconductance	$V_{DS} = 10 \text{ V}$ $I_{D} = 6 \text{ A}$		18		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25V f = 1 MHz, V_{GS} = 0$		800 180 32		pF pF pF

# **ELECTRICAL CHARACTERISTICS** (continued)

## **SWITCHING ON**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub> t <sub>r</sub>	Turn-on Delay Time Rise Time	$\begin{aligned} &V_{DD} = 15 \text{ V} & I_{D} = 3 \text{ A} \\ &R_{G} = 4.7 \Omega & V_{GS} = 2.5 \text{ V} \\ &(\text{Resistive Load, Figure 1}) \end{aligned}$		20 25		ns ns
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V <sub>DD</sub> = 15V I <sub>D</sub> = 6A V <sub>GS</sub> =2.5V (see test circuit, Figure 2)		6.8 2.0 3.4	9	nC nC nC

## **SWITCHING OFF**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>d(off)</sub> t <sub>f</sub>	Turn-off Delay Time Fall Time	$\begin{aligned} &V_{DD} = 15 \text{ V} & I_{D} = 3 \text{ A} \\ &R_{G} = 4.7\Omega, &V_{GS} = 2.5 \text{ V} \\ &(\text{Resistive Load, Figure 1}) \end{aligned}$		32 13		ns ns

### SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions		Тур.	Max.	Unit
I <sub>SD</sub> I <sub>SDM</sub> (•)	Source-drain Current Source-drain Current (pulsed)				6 24	A A
V <sub>SD</sub> (*)	Forward On Voltage	I <sub>SD</sub> = 6 A V <sub>GS</sub> = 0			1.2	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 6 \text{ A}$ $di/dt = 100 \text{A}/\mu \text{s}$ $V_{DD} = 15 \text{ V}$ $T_j = 150^{\circ}\text{C}$ (see test circuit, Figure 3)		25 21 1.7		ns nC A

<sup>(\*)</sup>Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %.
(•)Pulse width limited by safe operating area.

**Fig. 1:** Switching Times Test Circuits For Resistive Load

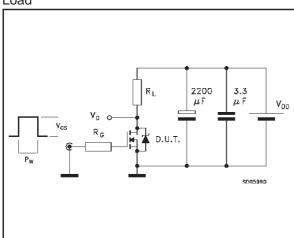


Fig. 2: Gate Charge test Circuit

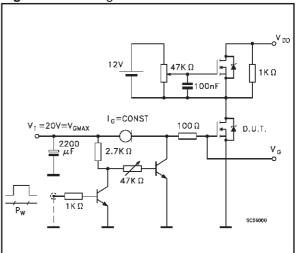
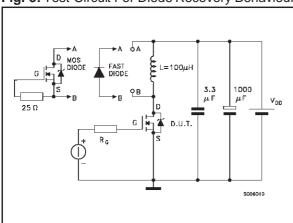
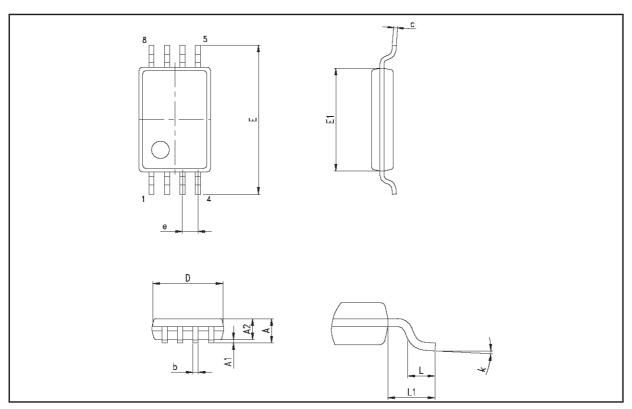


Fig. 3: Test Circuit For Diode Recovery Behaviour



# **TSSOP8 MECHANICAL DATA**

DIM.		mm.		inch.			
DIIVI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А	1.05		1.20	0.041		0.047	
A1	0.05		0.15	0.002		0.006	
A2	0.80		1.05	0.032		0.041	
b	0.19		0.30	0.008		0.012	
С	0.090		0.20	0.003		0.007	
D	2.90		3.10	0.114		0.122	
Е	6.20		6.60	0.240		0.260	
E1	4.30		4.50	0.170		0.177	
е		0.65			0.025		
L	0.45		0.75	0.018		0.030	
L1		1.00			0.039		
k	00		80	0.192		0.208	



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